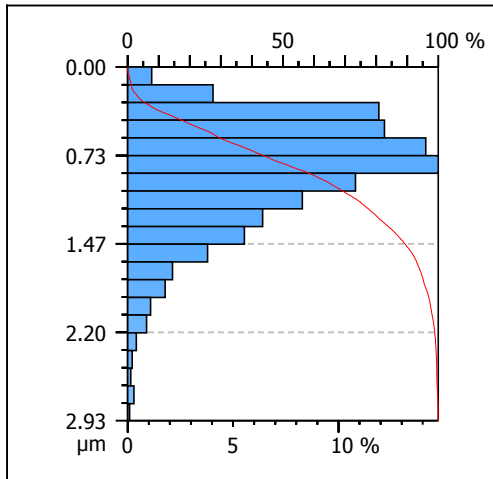


TSS Analysis of 2D Surface Roughness Measurement



Name: Project and Measured Item Names here

Date: 22-Dec-22



ISO 4287

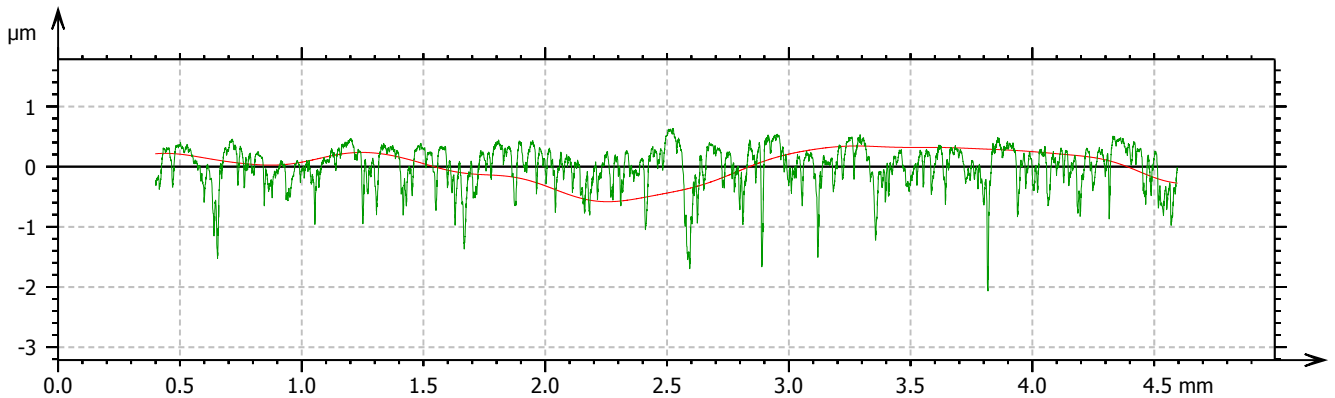
Amplitude parameters - Roughness profile

Ra	0.260	µm	Gaussian filter, 0.8 mm
Rp	0.521	µm	Gaussian filter, 0.8 mm
Rsk	-1.35		Gaussian filter, 0.8 mm
Rz	2.19	µm	Gaussian filter, 0.8 mm
Rq	0.341	µm	Gaussian filter, 0.8 mm
Rt	2.70	µm	Gaussian filter, 0.8 mm
Rv	1.66	µm	Gaussian filter, 0.8 mm
Rc	0.800	µm	Gaussian filter, 0.8 mm, ISO 4287 w/o amendment 2

Material ratio parameters - Roughness profile

Rmr (Rz/4)	71.0	%	c = Rz/4 µm under the ref, 5%, Gaussian filter, 0.8 mm
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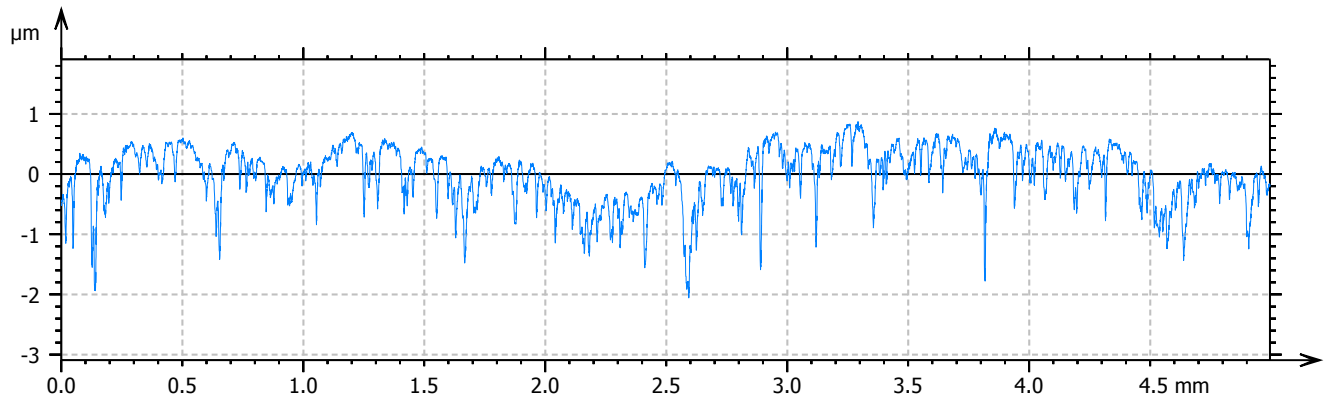
Filtered profiles - Levelled (Least squares method)



Information

Profile	Roughness profile & Waviness profile
Filter settings	Gaussian filter, cut-off 0.800 mm

Profile curve - WS_8-4



Parameters

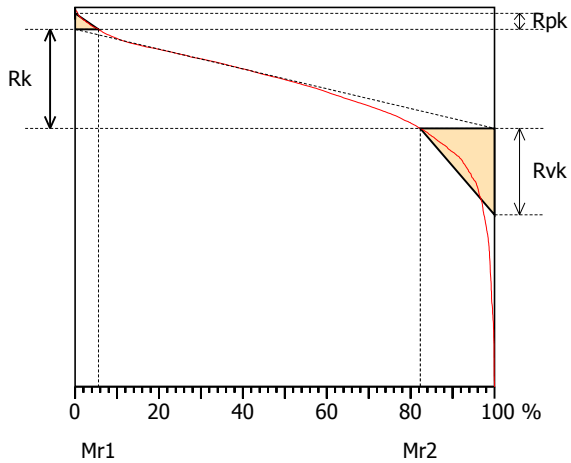
Length	5.00	mm
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TSS Analysis of 2D Surface Roughness Measurement



Name:

Date: 22-Dec-22



Information

Filter settings Double Gaussian filter, 0.800 mm.

Parameters

Parameters	Value	Unit
Rk	0.689	μm
Rpk	0.111	μm
Rvk	0.601	μm
Mr1	5.58	%
Mr2	82.3	%
A1	3.10	$\mu\text{m}^2/\text{mm}$
A2	53.2	$\mu\text{m}^2/\text{mm}$
Rpk*	0.152	μm
Rvk*	1.80	μm